

PATENT NUMBER

OLPE

PATENT DATE

OLPE.
SCANNED TRI 02/10/11

APPLICATION NO. 09/960441	CONT/PRIOR	CLASS 257	SUBCLASS 414	ART UNIT 2815	EXAMINER <i>William Lee</i>
APPLICANTS Newell Chiesl		438	48	2712	A. Wilson Simkovic
TITLE	Arrangement for measuring pressure on a semiconductor wafer and an associated method for fabricating a semiconductor wafer				

PTO-2040
12/99

[illegible]

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (Date) has been disclaimed.	_____ (Assistant Examiner) _____ (Date)			NOTICE OF ALLOWANCE MAILED	
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____	_____ (Primary Examiner) _____ (Date)			Amount Due	Date Paid
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